

Notice of References Cited	Application/Control No. 10/575,346	Applicant(s)/Patent Under Reexamination SAITO ET AL.	
	Examiner PATRICIA L. HAILEY	Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,219,443 A	08-1980	Klinedinst et al.	502/101
*	B	US-5,158,843 A	10-1992	Batson et al.	429/231.8
*	C	US-5,494,562 A	02-1996	Maley et al.	257/414
*	D	US-5,696,314 A	12-1997	McCaffrey et al.	205/778
*	E	US-5,707,763 A	01-1998	Shimizu et al.	429/217
*	F	US-6,447,571 B1	09-2002	Ito et al.	75/255
*	G	US-2005/0272595 A1	12-2005	Kobayashi et al.	502/101
*	H	US-7,098,163 B2	08-2006	Hampden-Smith et al.	502/101
*	I	US-7,141,270 B2	11-2006	Wittpahl et al.	427/115
*	J	US-7,279,015 B2	10-2007	Merker, Udo	29/25.03
*	K	US-2005/0116375 <i>06/2005</i>	02-2009	Ito, Junji	264/105
*	L	US-7,713,899 B2	05-2010	Hampden-Smith et al.	502/101
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2006064342 A2	06-2006	World Intellect	SAITO et al.	B41J 2/06
	O	01/80338	10-2001	WO	Scherson	H01M 6/18
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.